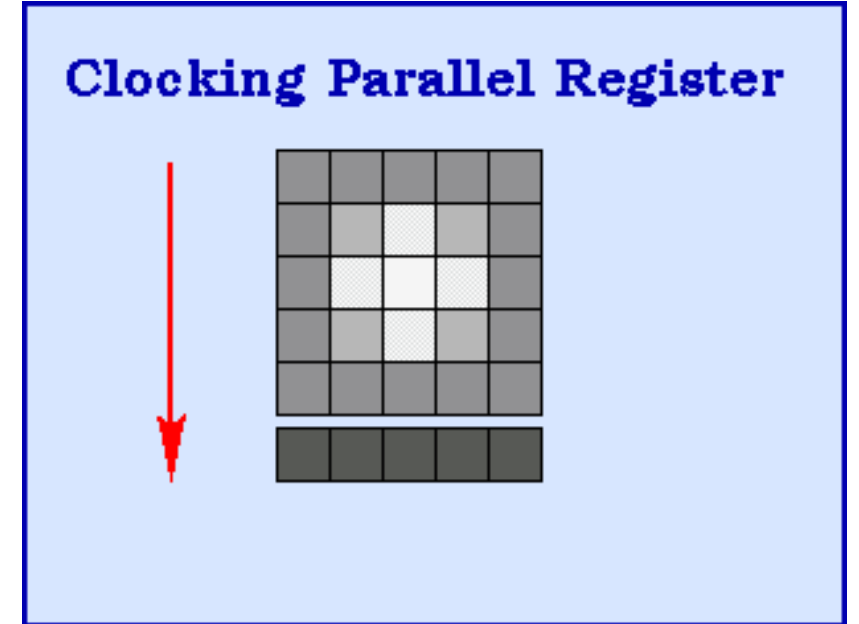
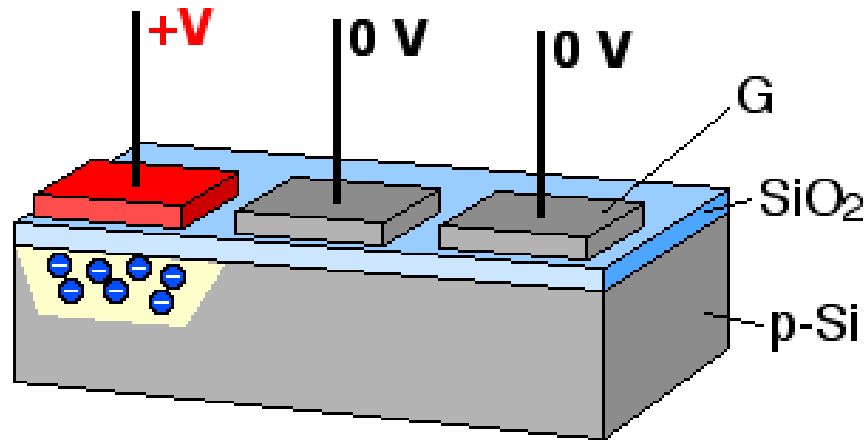
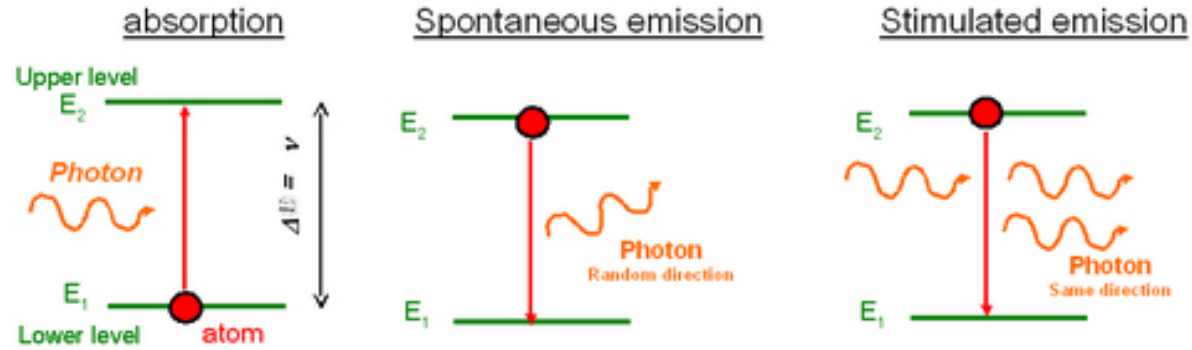


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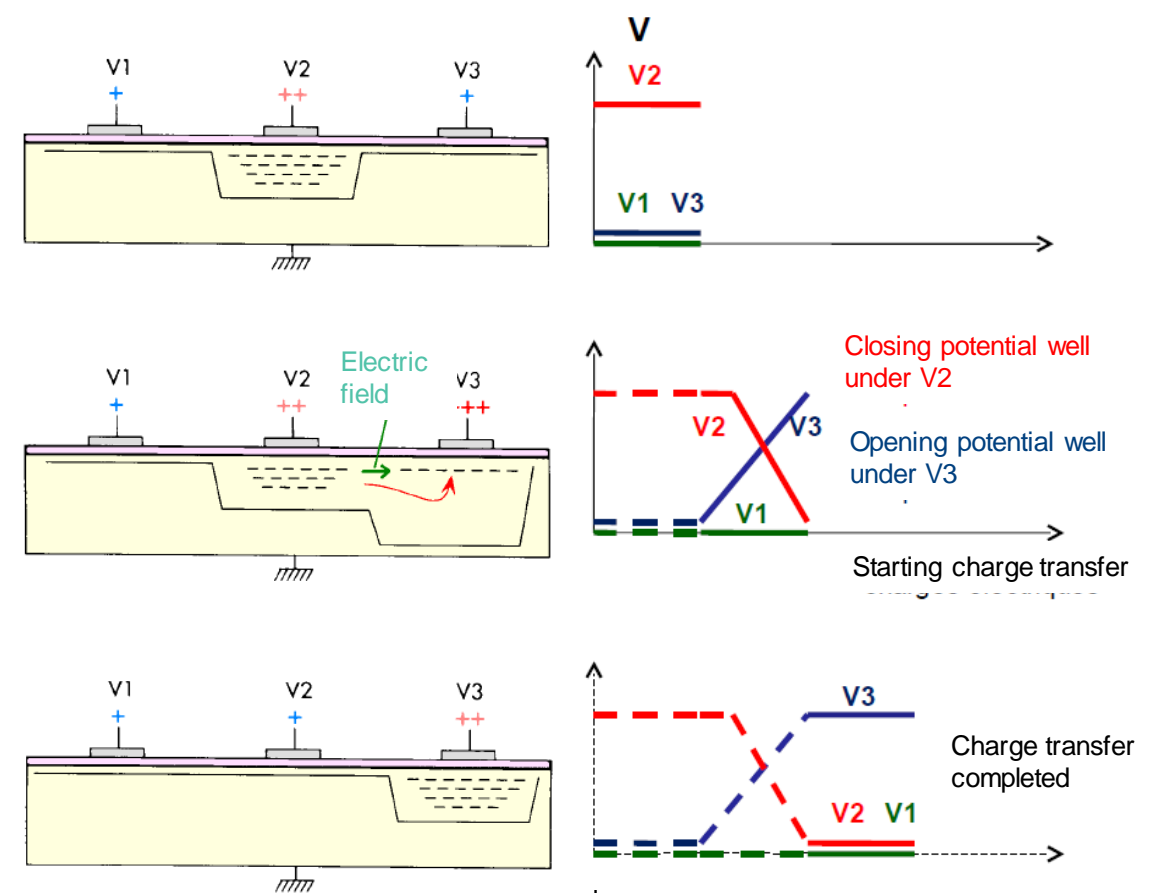
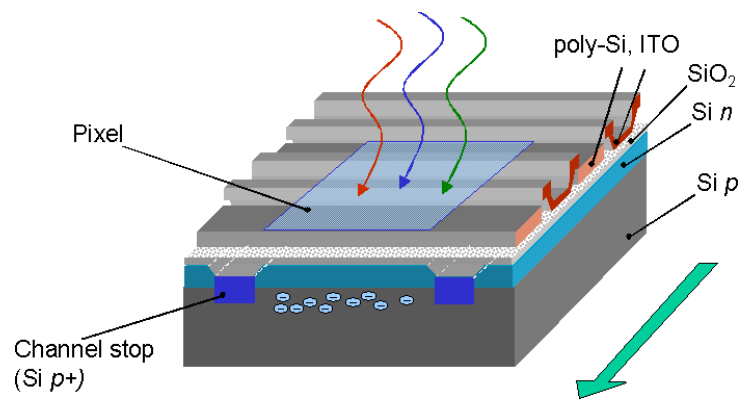
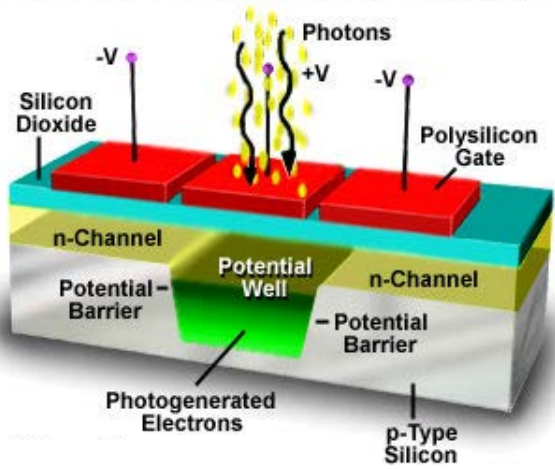
Detection lab

J.-G. Cuby

Credits: Hervé Le Coroller & Christophe Adami, LAM



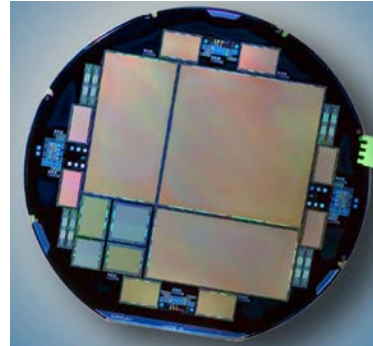
Metal Oxide Semiconductor (MOS) Capacitor



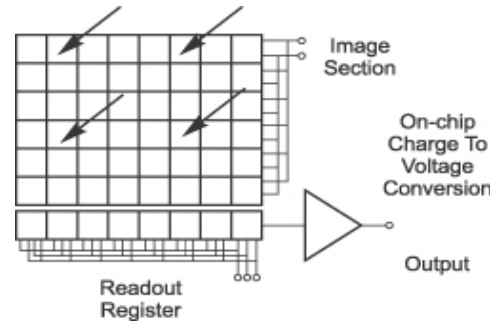
- Charges are collected under electrodes (as long as the voltage is applied)
- Charges are then transferred pixel to pixel by adequate clocking of the electrodes

A large variety of CCDs

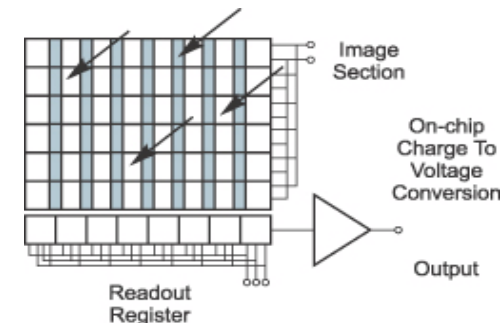
Formats



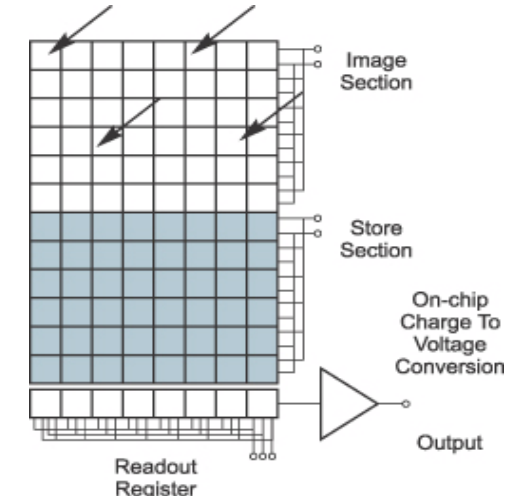
Readout architecture



Full frame CCD

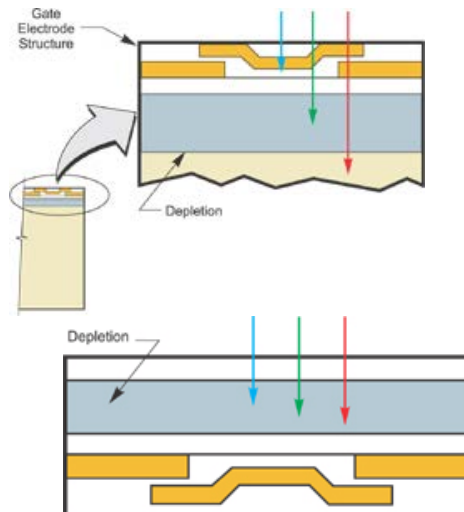


Interline transfer CCD



Frame transfer CCD

Frontside vs backside illumination



Frontside and Backside Illuminated CCDs

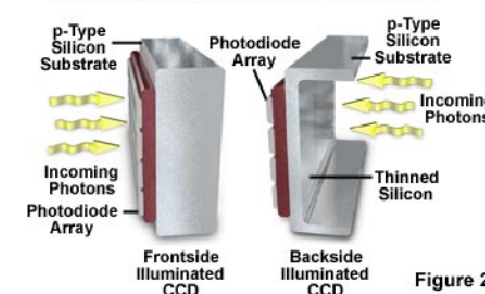
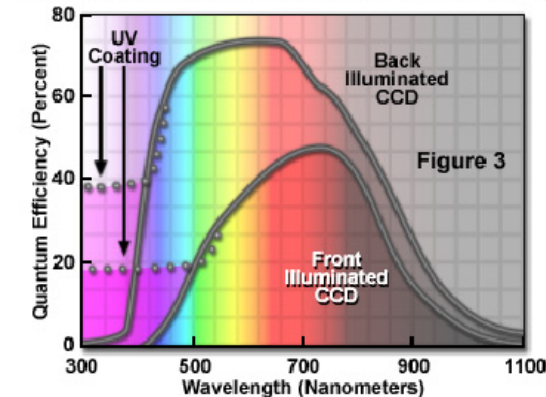


Figure 2
ur
Initi

Frontside and Backside CCD Quantum Efficiency

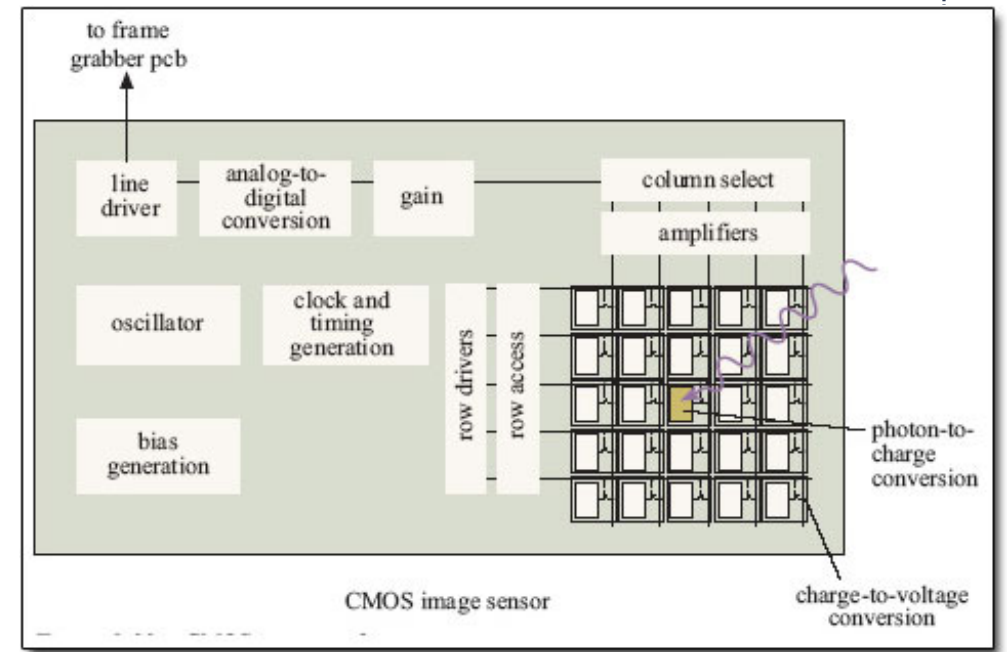
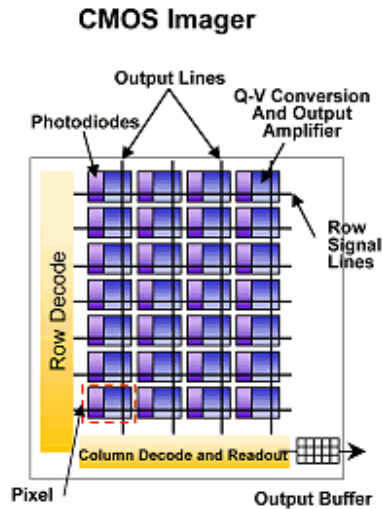


CMOS, infrared detectors

CMOS

CMOS vs. CCDs

Infrared detectors



Lower fill factor (hence QE). Higher readout noise. Higher readout speed. No blooming. Integration of processing functions. Lower electrical consumption. Less expensive

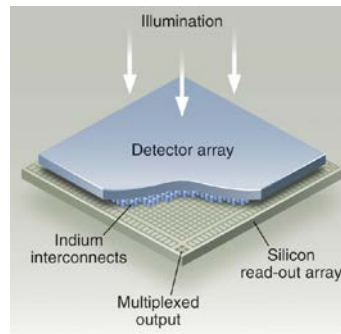
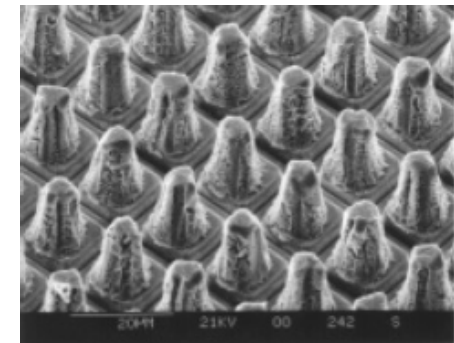
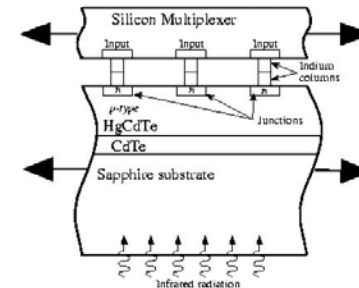
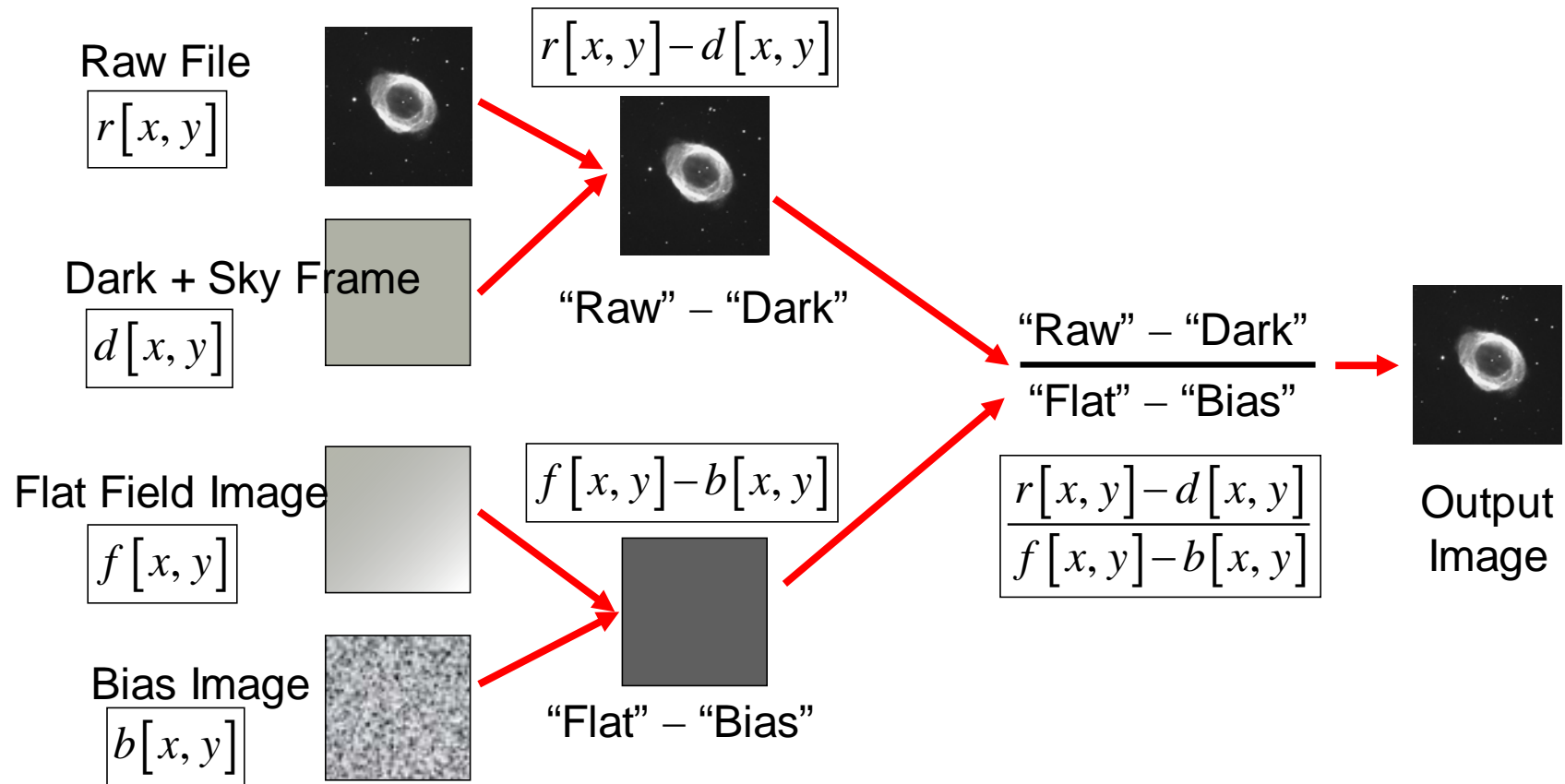


Figure 7.1: Cross-section of a NICMOS3-type detector (not to scale)

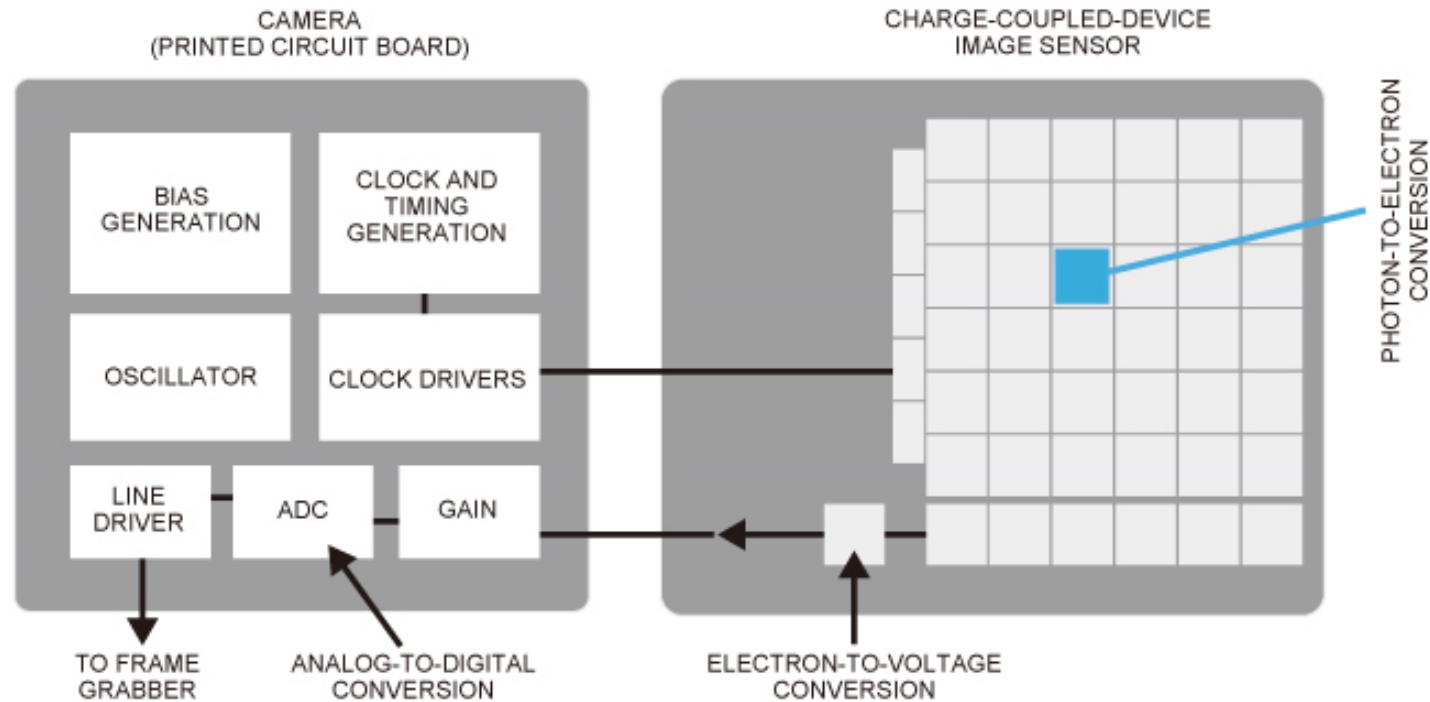


Hybridization of the detector layer to a CMOS readout circuit

Correction of Raw Image with Bias, Dark, Flat Images



CCD gain



Pixel intensities end up as digital numbers ('counts') – in Analog to Digital Units (ADU). If you want to relate these numbers to the original number of electrons stored in the pixels, you need to know the conversion factor that is called the CCD gain g (in $e^- \text{ADU}^{-1}$).

Basics of noise

- The variance of the sum of independent random variables is the sum of the variances
- The sum of N random independent variables (with finite means and variances) tends to a normal (gaussian) distribution
- A series of random events occurring continuously and independently of one another is described by a Poisson distribution:

$$\text{Prob}(N, \bar{N}) = \frac{(\bar{N})^N e^{-\bar{N}}}{N!}$$

$$\text{Variance: } \text{Var}(N) = \bar{N}$$

$$\text{Standard deviation: } \sigma = \sqrt{\bar{N}}$$

where N is the measured number of events (counts), \bar{N} the mean of N , Var is the variance and σ the standard deviation

Sources of signal and noise

Let's assume that the CCD is illuminated by a uniform and stable source of light generating M_{e^-} electrons per second ($e^- s^{-1}$) (per pixel)

CCD gain in $e^- ADU^{-1}$

g

Readout noise (e^- rms) (per pixel)

R (random variable added to the signal, $\bar{R} = 0$ and variance R^2)

Measurement

$$M_{ADU} = g^{-1} \times (M_{e^-} + R)$$

Average

$$\overline{M_{ADU}} = g^{-1} \times \overline{M_{e^-}}$$

Variance

$$\text{Var}(M_{ADU})$$

Using the noise properties of the signal, expected to follow a Poisson distribution, it is possible to derive the CCD gain and noise.

Lab summary

- Get familiarized with a CCD, take images, change parameters (integration time, temperature, etc.)
- Do basic image processing (bias and dark frame subtraction, flat-fielding)
- Do basic statistical analysis (histograms, average, standard deviation)
- Study the statistical properties of the dark current at different temperatures
- Study the CCD linearity range
- Determine the gain and readout noise of the CCD from the statistical properties of the measured signal

